



FUDAN
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R&D for KLM upgrade

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51st B2GM KLM Parrel Session

June. 13, 2025

- Last B2GM:

- ◆ Development of MPT2321 back-end system:

- 1. Development of test system

- This B2GM:

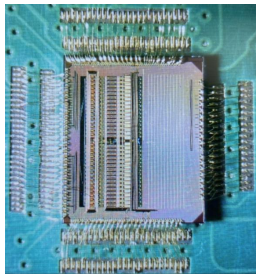
- ◆ Test of MPT2321 back-end system:

- 1. Single photon spectrum
 - 2. Signal to noise ratio
 - 3. TDC performance
 - 4. Power consumption

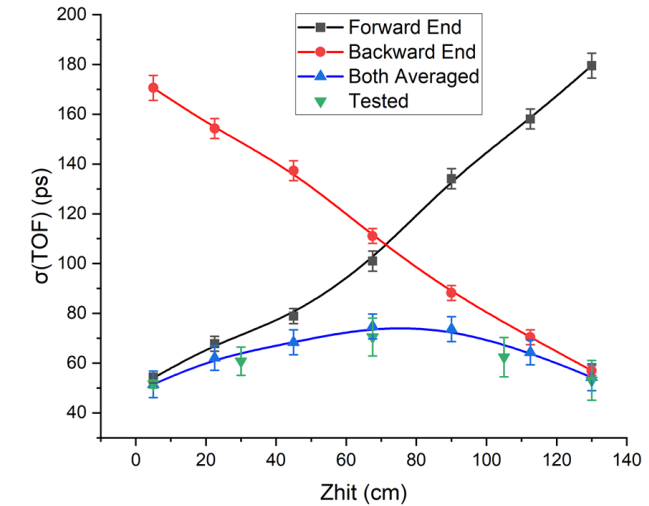
- Front end test results
 - 1. Time resolution of 1.35m-long GNKD scintillators is less than 70 ps.
 - 2. Time resolution of new 50cm-long GNKD scintillators is about 45 ps.
- The development of front end is almost done.

Back end electronics is needed !!!

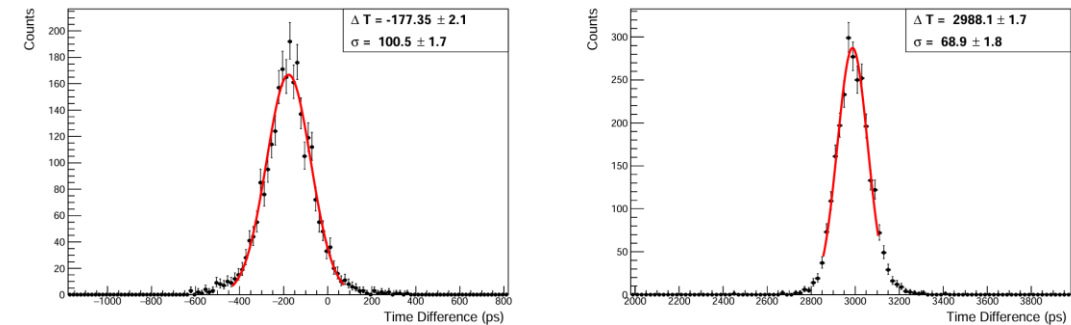
- The development of Back-end electronics system based on MPT2321 chip is progressing.



MPT2321 chip



Time resolution as a function of scintillator position



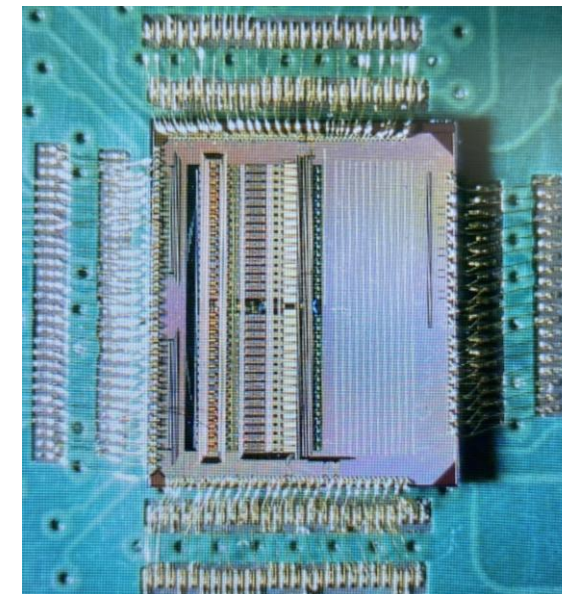
GNKD_4 scintillator's central position time resolution test using dual-end read out scheme

Introduction of MPT2321 chip

The MPT2321 chip is a SiPM signal processing SoC chip designed for high-precision time-of-flight signal processing.

Features

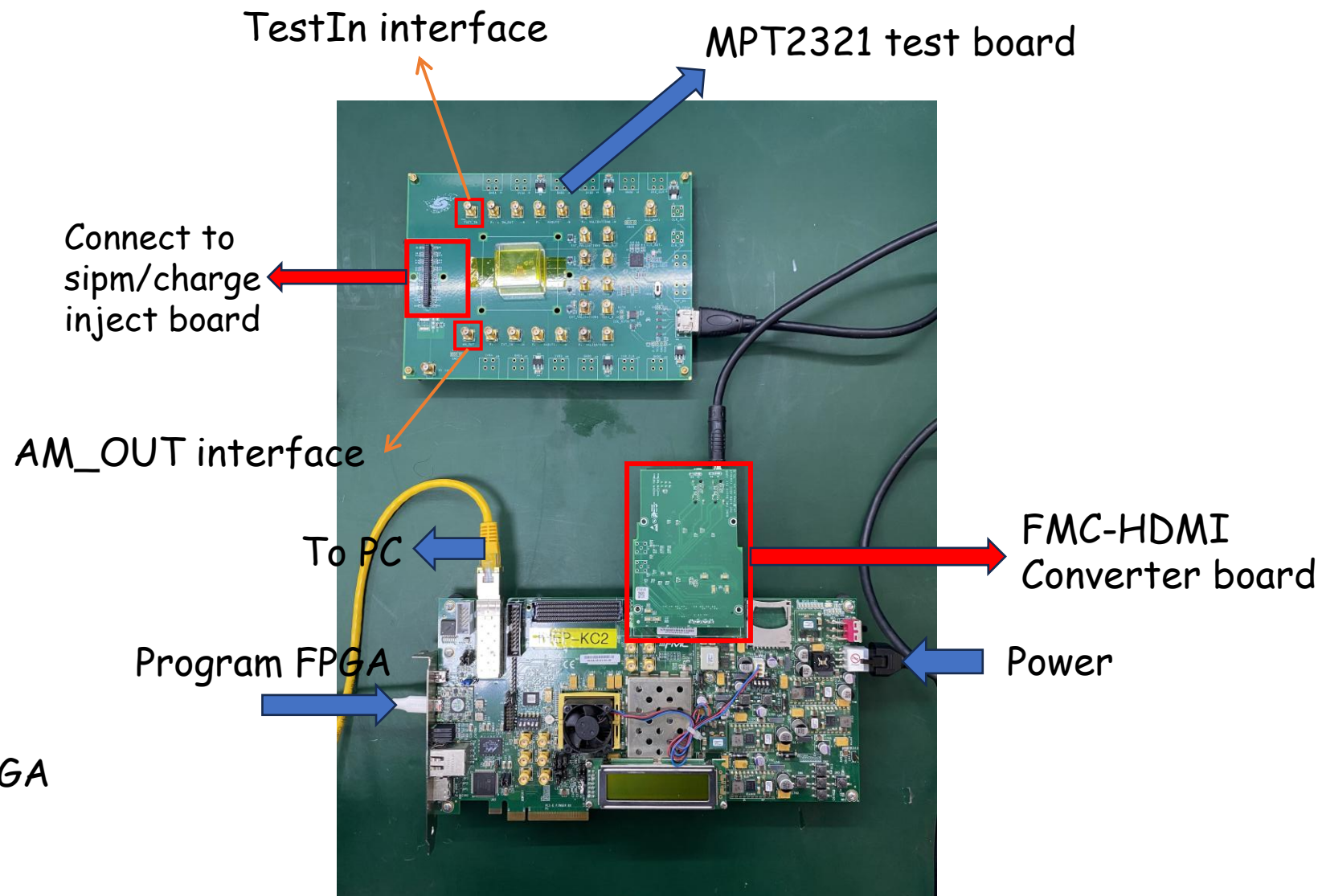
- 32 input channels
- Automatically select the range of measurement signals
- 50ps precision 20-bit TDC
- 12bit ADC
- Complete on-chip signal processing
- Standard IIC Bus Control
- 8b10b encoding transmission
- Multichannel LVDS data transmission
- 12 Mcps transmission event rate
- High integration, low power consumption
- 200M data transmission rate
- The maximum charge measurement dynamic range is 2.4 nC
- Minimum detectable signal range 4fC



MPT2321 chip

宇称电子
—MICROPARTY—
Sensor and Science

- FPGA Board: KC705 of Xilinx
- Signal input to MPT2321
 - Female Header
 - TestIn interface
- MPT2321 to FPGA
 - HDMI
 - FMC-HDMI Converter
- FPGA to PC
 - RJ45-SFP converter
 - USB-JTAG to program FPGA



Test Results - Charge inject linearity

- Measurement Method

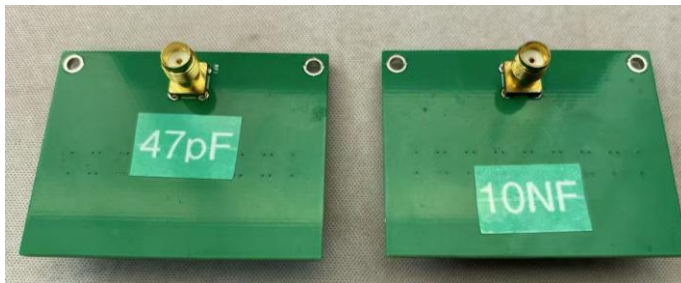
- Inject Pulse through Charge inject board

- Injected Charge: $Q = \Delta V \times C$

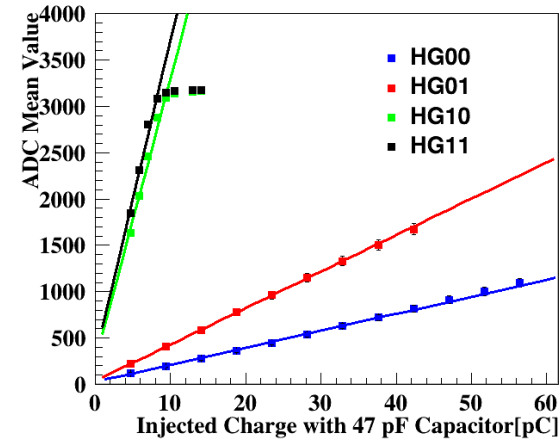
- Capacitor of Charge inject board

- High-Gain mode: 47pF

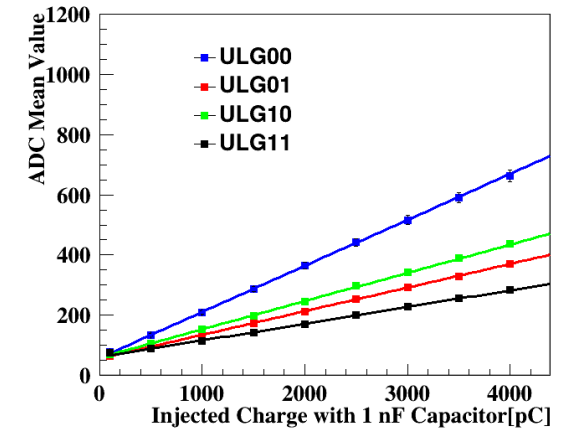
- Low-Gain mode: 1nF



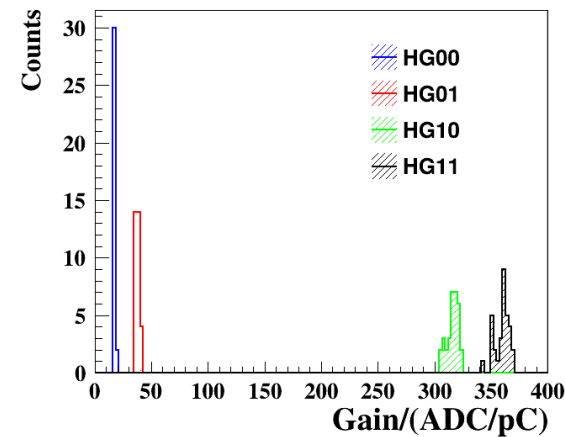
Charge Injection board



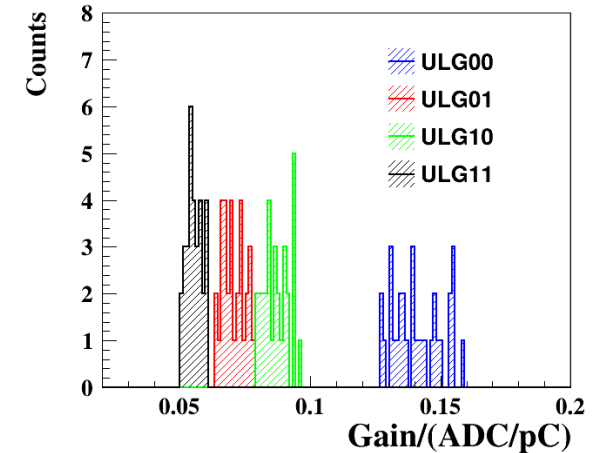
High-Gain mode



Low-Gain mode



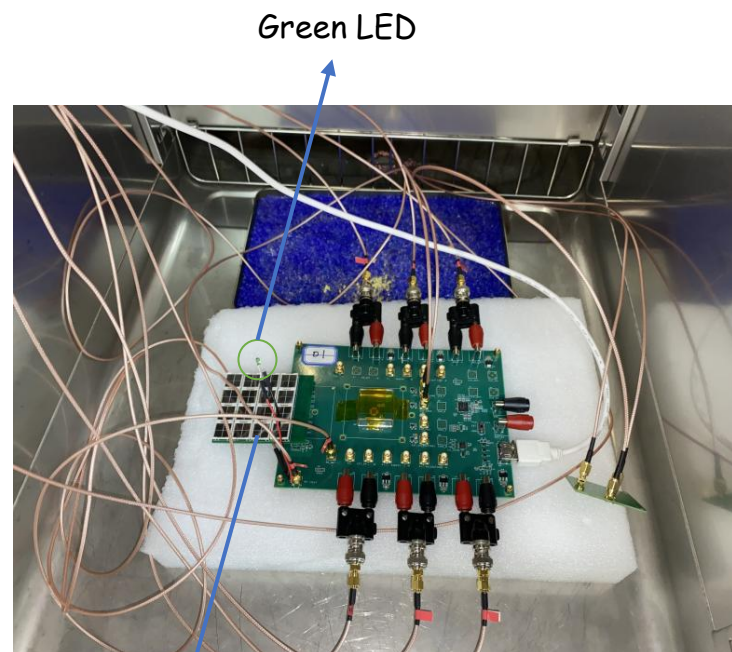
High-Gain mode



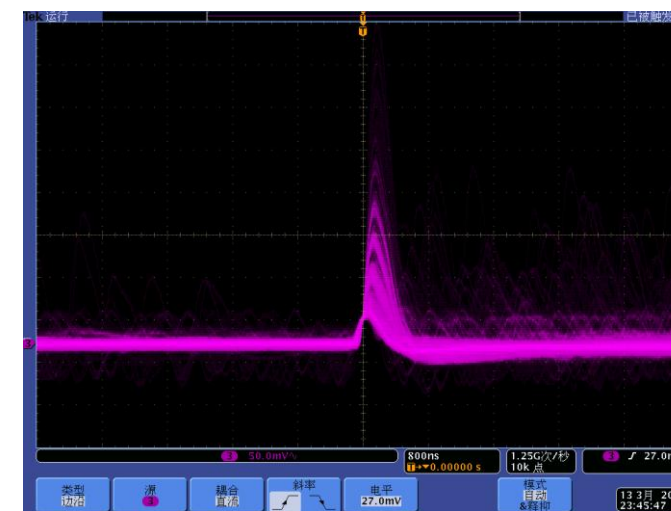
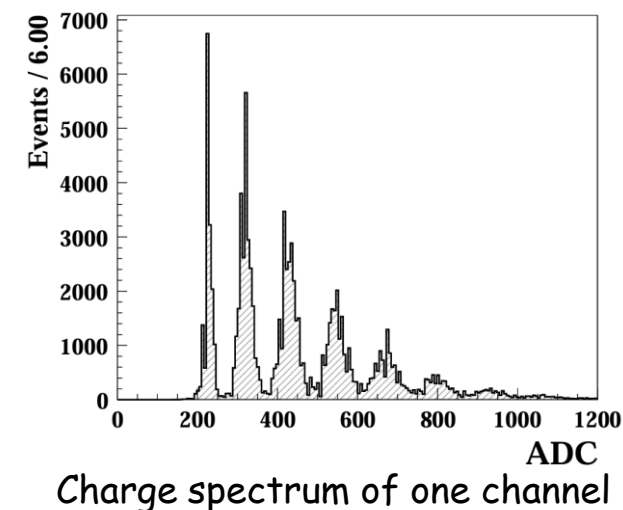
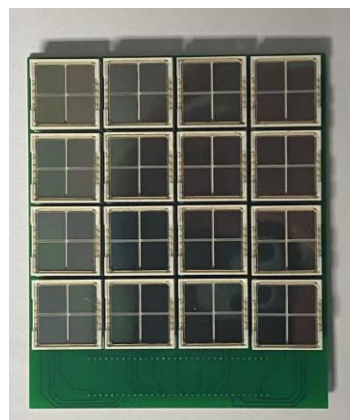
Low-Gain mode

Test Results - Charge spectrum

- SiPM type: S13371-6050CQ-02
- Measurement Method
 - Green LED drove by pulse signal
 - Pulse signal
 - Width: 10 ns
 - Amplitude: 1.070 V
- Using external trigger mode
 - Same frequency with LED driver pulse



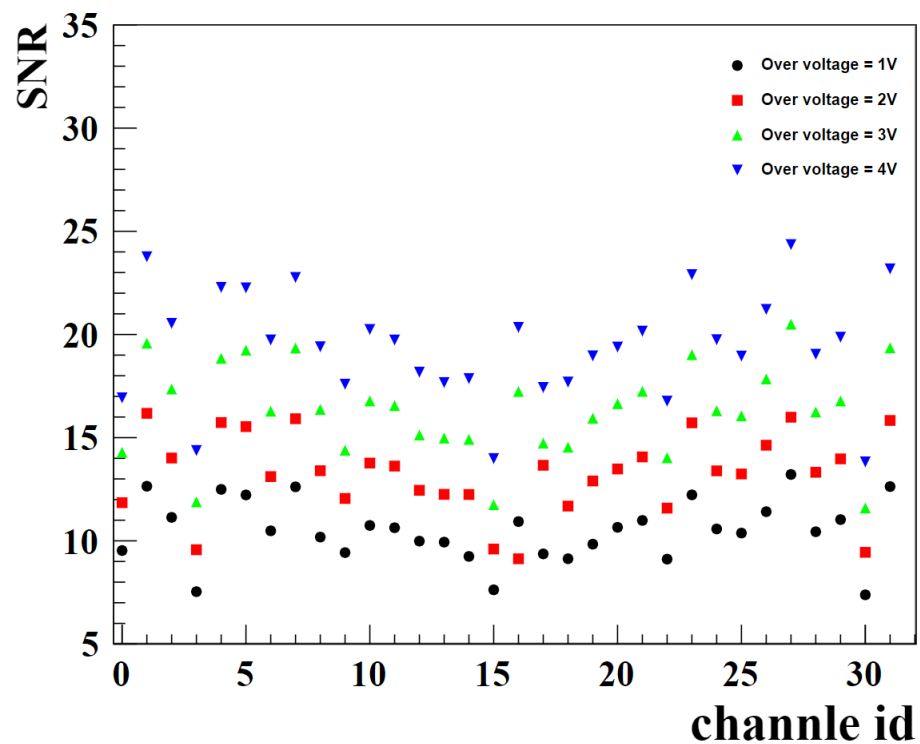
8x8 SiPM array Setup



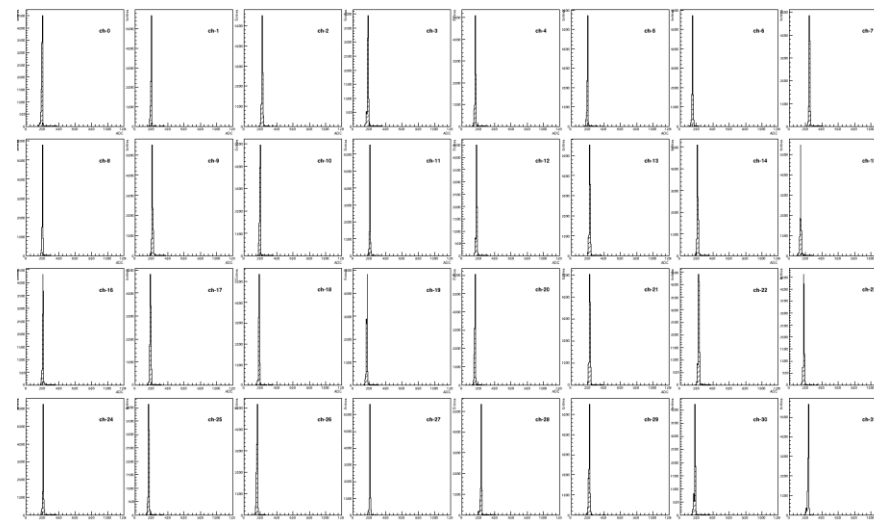
Waveform from AM_OUT

- Signal-to-noise ratio

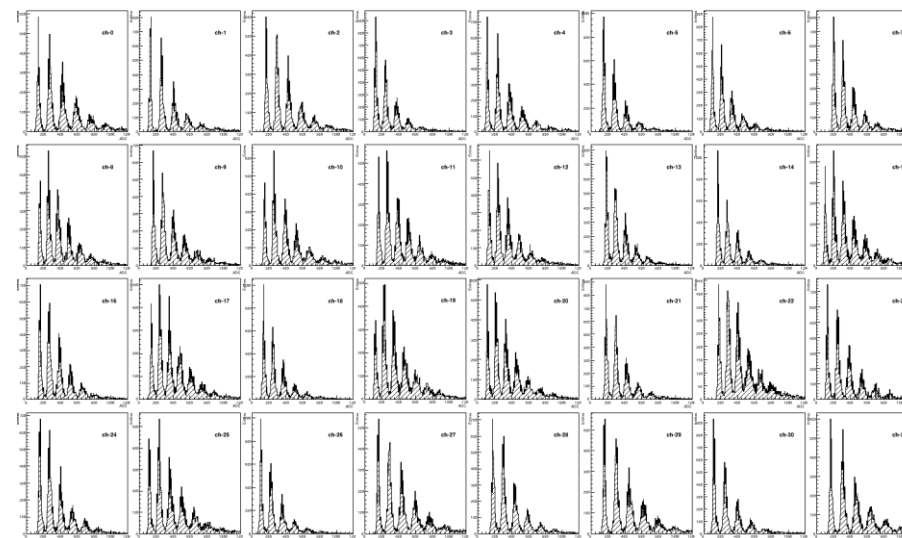
- Ratio of the gain and the standard deviation of the pedestal



SNR of each channel

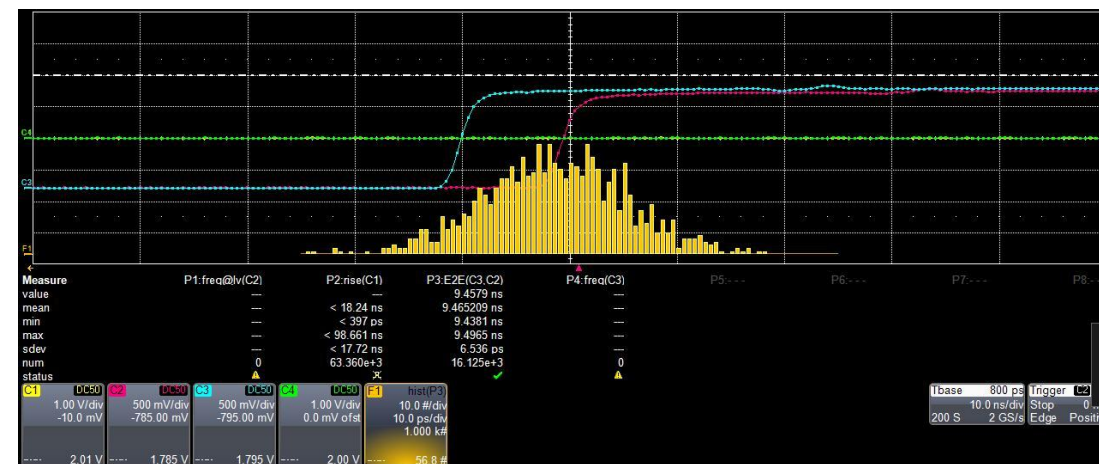


Distribution of pedestal of each channel

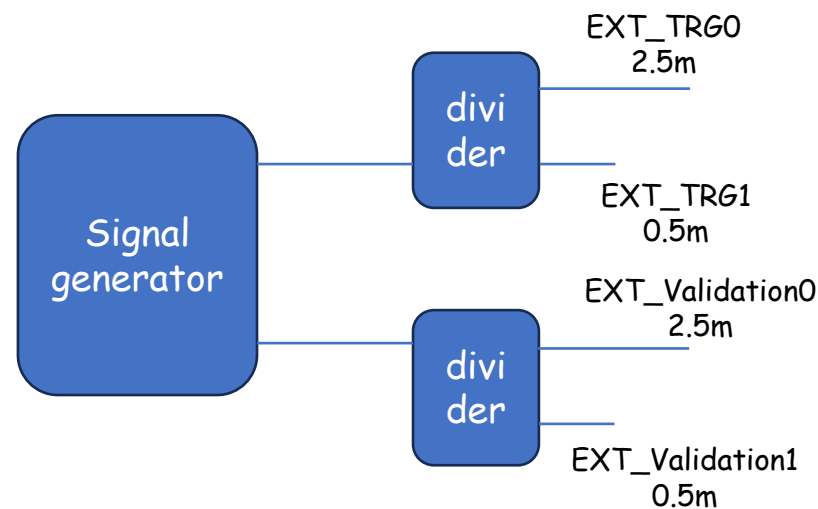


Charge spectrum of each channel

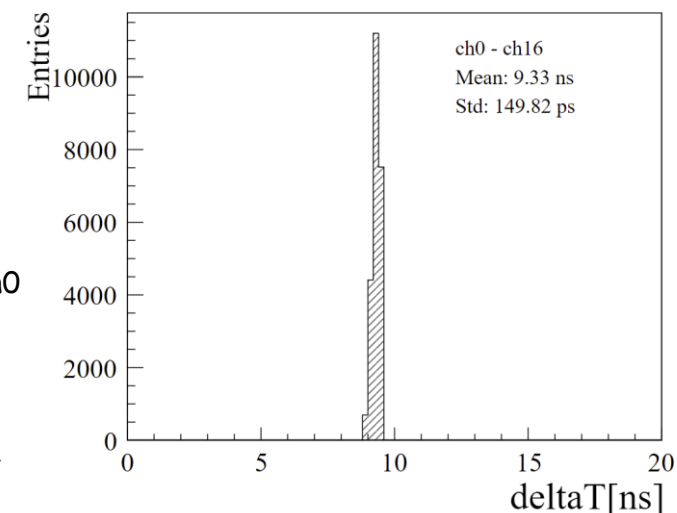
- Cable delay method
 - The difference of the length of two cable is 2m
- Time difference
 - oscilloscope: 9.47 ns
 - MPT2321: 9.33 ns
- Time resolution: ~ 150 ps
- Frequency of TDC clock: 80MHz



Cable delay measured by oscilloscope



Setup

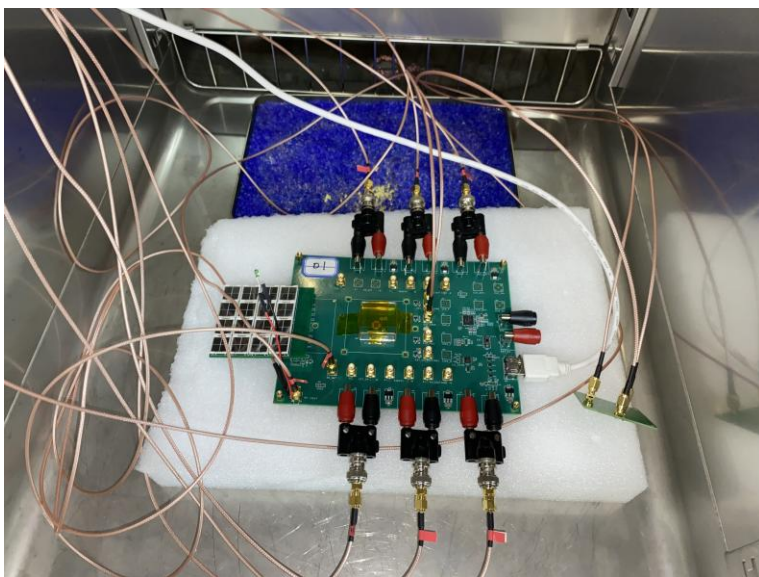


Cable delay measured by MPT2321

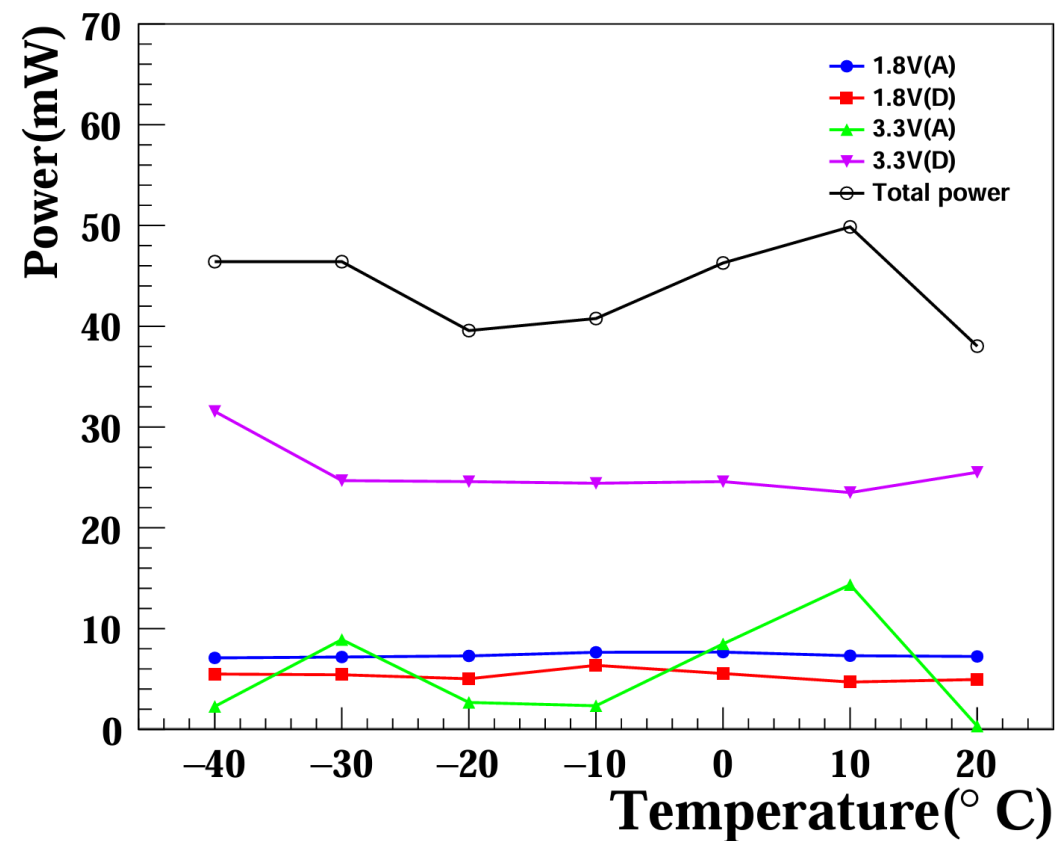
- Measurement method

- The board is set in a thermostat
- Monitor the current of power supply interface

- The Power consumption is stable at $-40^{\circ}\text{C} \sim 20^{\circ}\text{C}$



Setup



Power consumption vs Temperature

Summary:

- ✓ Test of Basic performance of MPT2321
 - ✓ Charge inject linearity
 - ✓ Charge spectrum
 - ✓ Signal to noise ratio
 - ✓ Power consumption

Plan:

- ❑ Fix known bug of firmware (decode module)
- ❑ Develop trigger logic

Thanks for your attention!!!

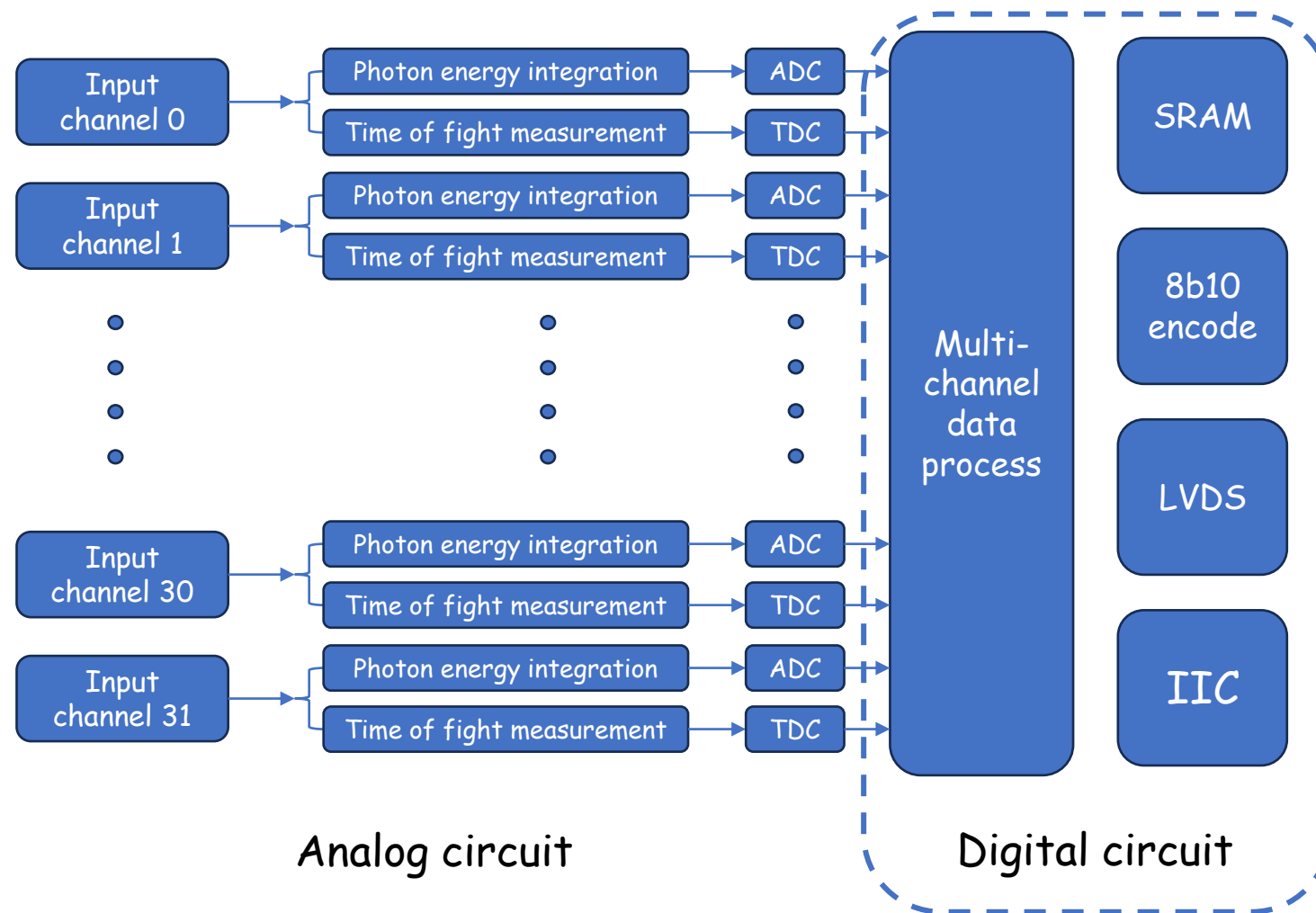
Backup

- Analog circuit

- 12bits ADC module
- 50ps precision TDC

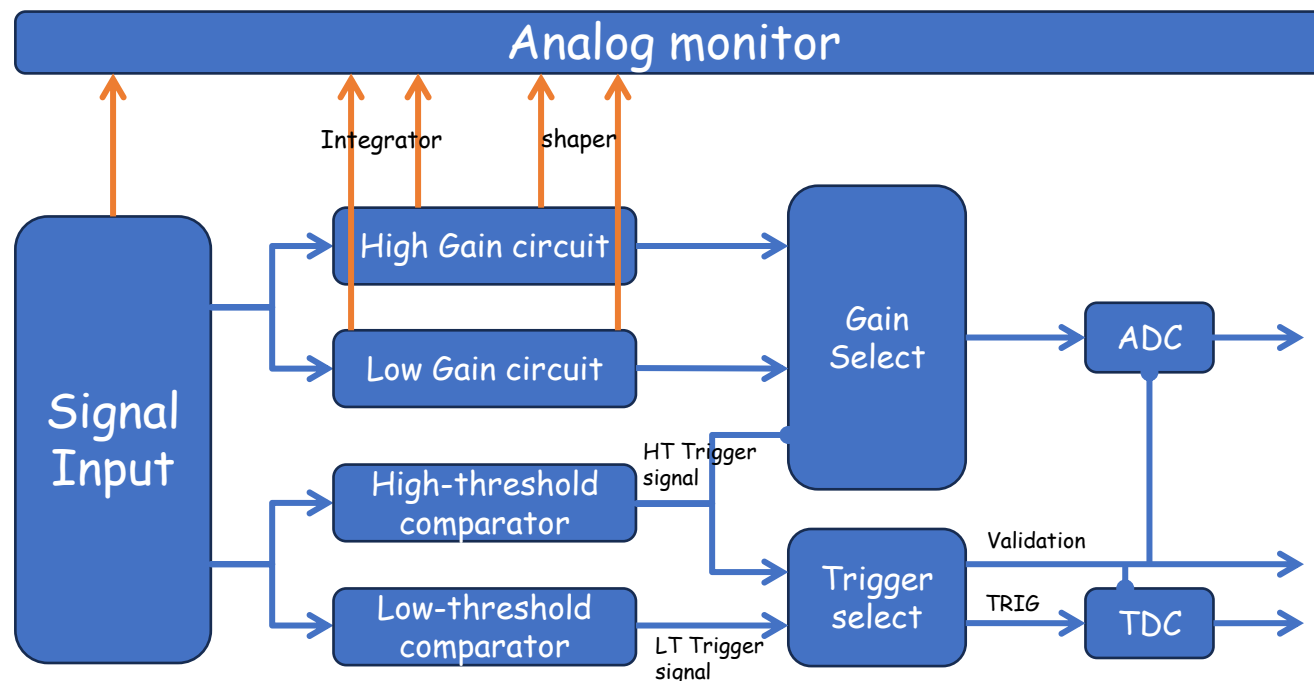
- Digital circuit

- Control of chip status
- Data processing, compression and output



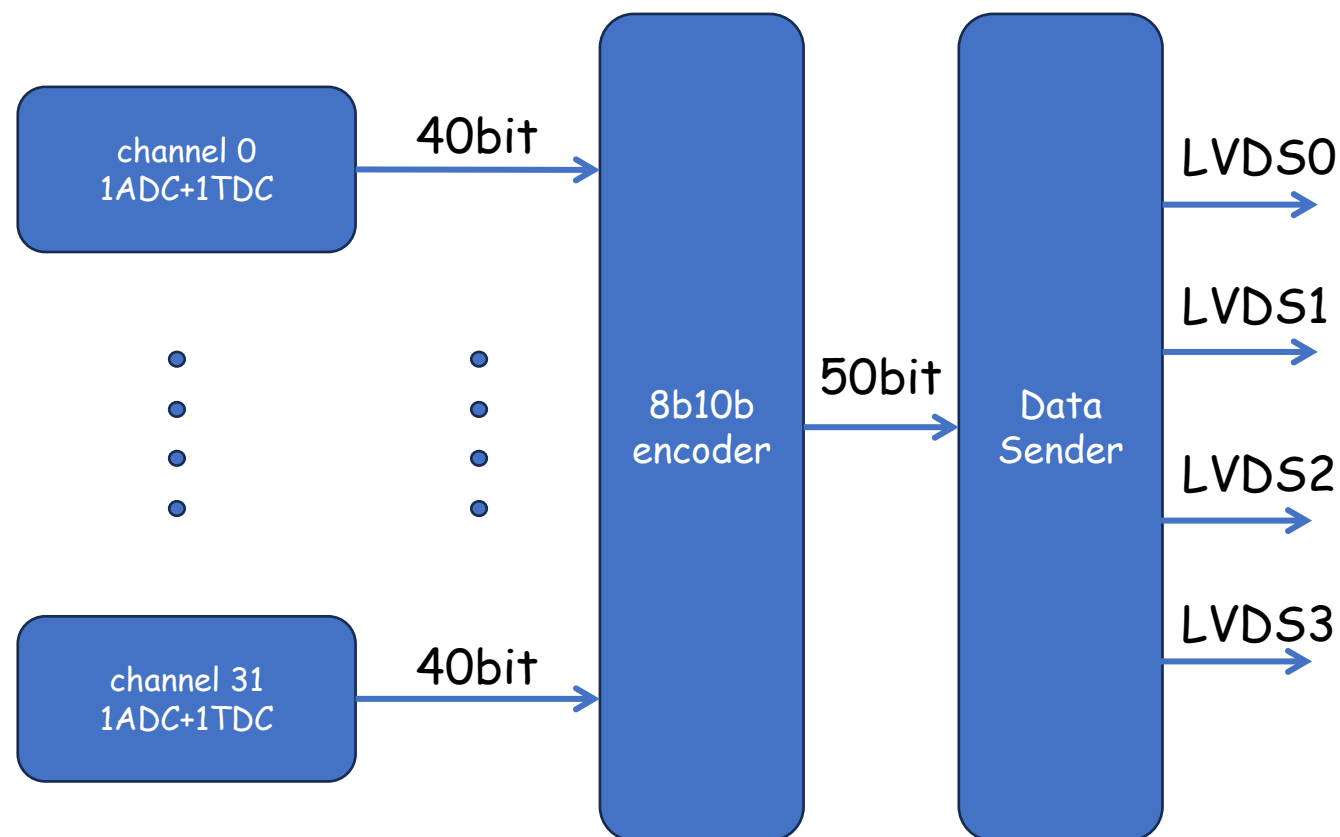
Analog signal process

- Two Gain circuit
 - Four mode for high gain
 - Four mode for low gain
- Two threshold comparator
 - High-threshold comparator determine gain
 - Low-threshold comparator determine arrival time and trigger
- Event validity flag (Validation)
- TDC trigger signal (TRIG)
- Analog monitor (AM)



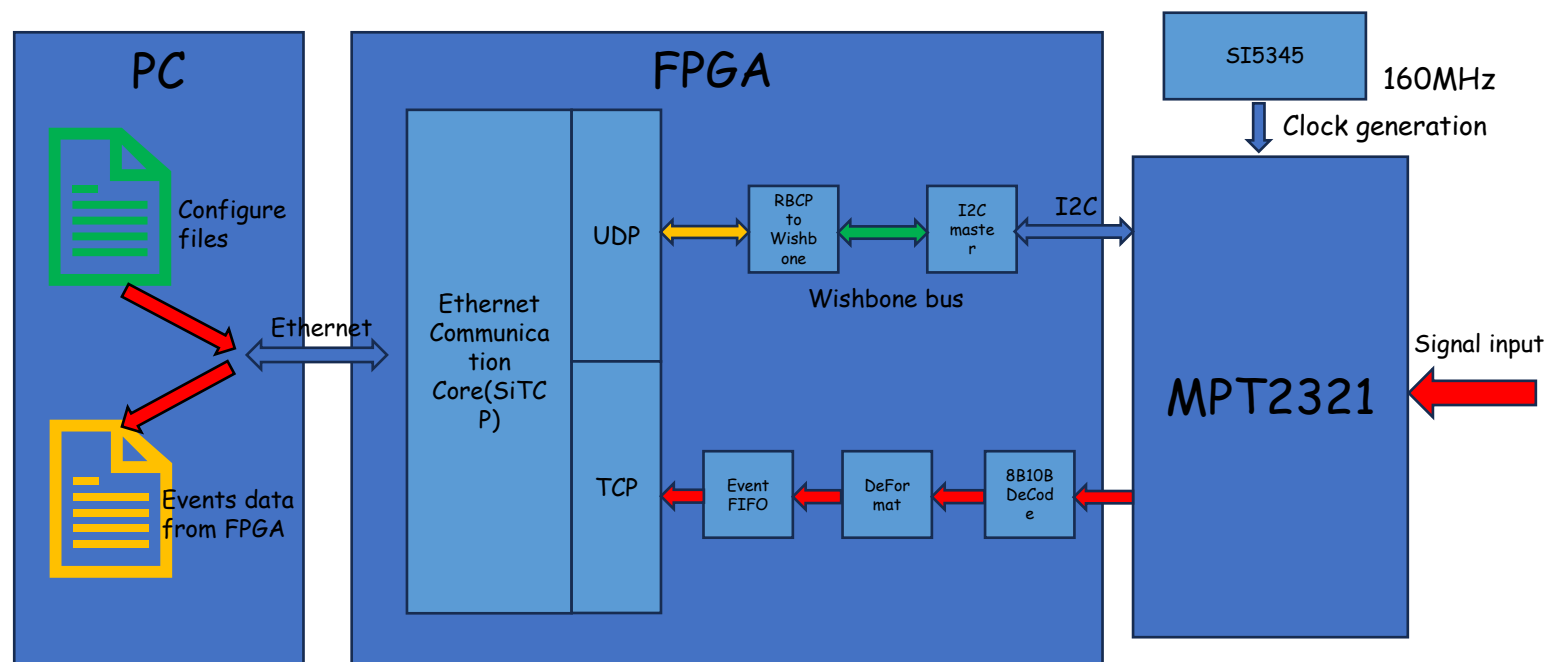
Digital signal process

- ADC and TDC data from each channel
 - 40 bits
- 8b10b encoder
 - 40 bits to 50 bits
- LVDS data transmission
 - Three transmission mode
 - Maximum event rate: $\sim 1/(60 \text{ Tsys})$



Structure of MPT2321 test system

- MPT2321 test board
 - 160 MHz Clock by SI5345
 - Important pin can be monitored through SMA interface
- FPGA
 - Communication Core: SiTCP
 - Configure MPT2321 through UDP
 - Decode, deformat and receive data through TCP
- PC
 - Configure script
 - DAQ script (Multithread)
 - Language: Python



IEEE transactions on nuclear science, 2008, 55(3): 1631-1637.

MPT2321 readout development

Optimization of configure parameter

- 基线调整
 - 调节SH_ped, 高增益整形输出
基线为300mV左右
 - 调节DIFF_ped, 选择后N输出
基线为1.7V左右
 - 调节CM_ped, 选择后P输出基线
为300mV左右
- 扫描最优低阈值
- 扫描hold delay参数
- 自动化脚本进行扫描

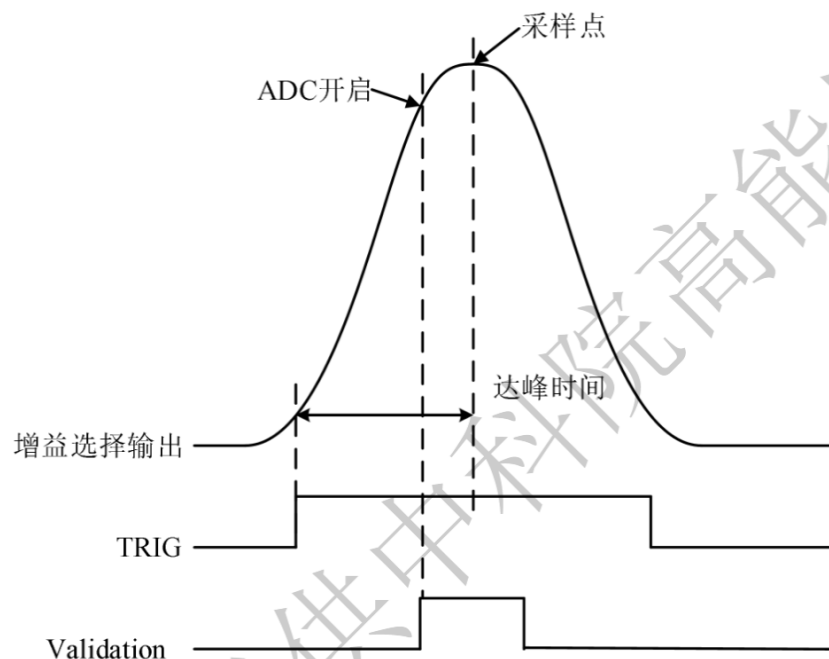


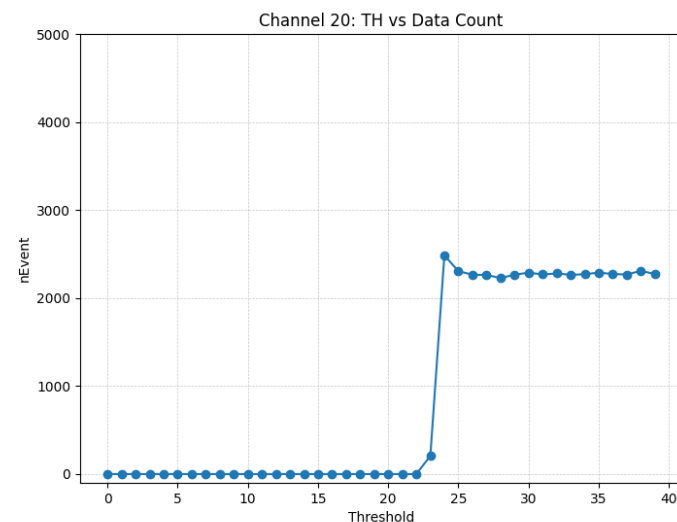
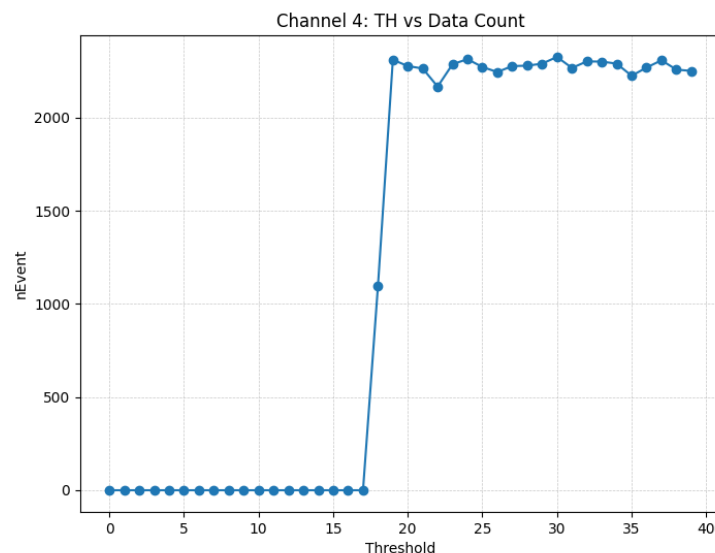
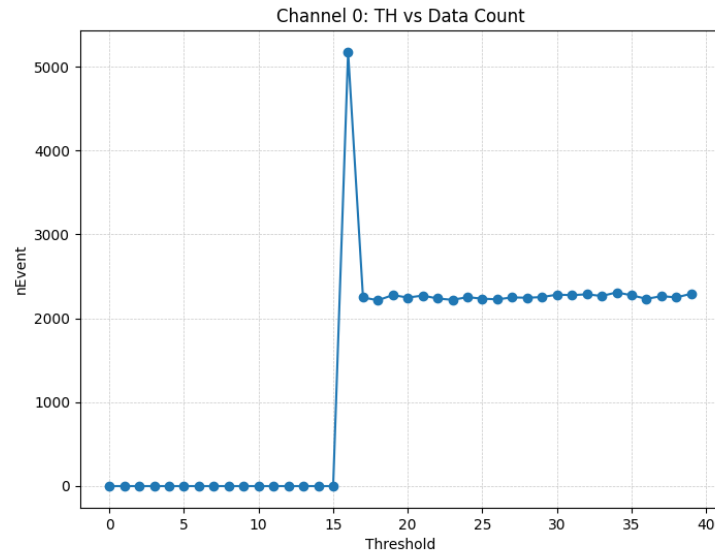
图 2.3 ADC 信号采样示意图

MPT2321 readout development

Optimization of configure parameter

● 低阈值扫描

- 通过电荷注入板注入信号
- 逐个通道设置一个阈值
 - 其他通道阈值设为最大
- 每次采集数据时间固定
 - 注入频率2kHz
 - 采集2s
 - Python脚本中数据解析丢包
- 采集数据跳变处为基线对应阈值



MPT2321 readout development

Optimization of configure parameter

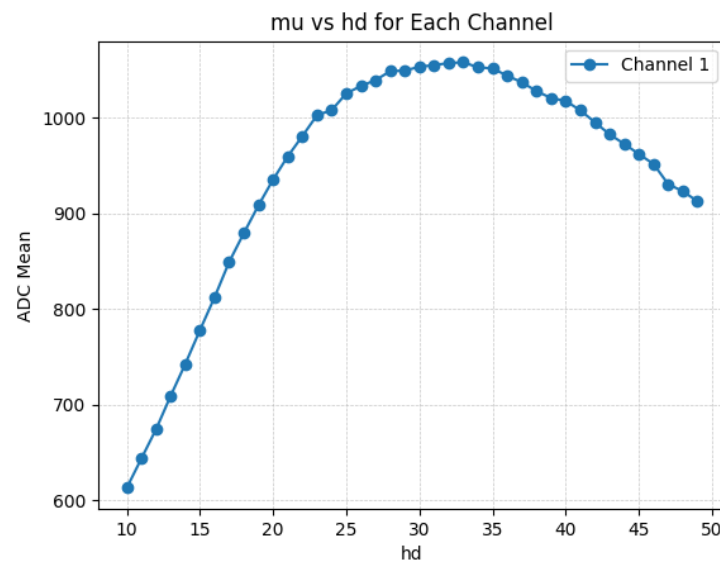
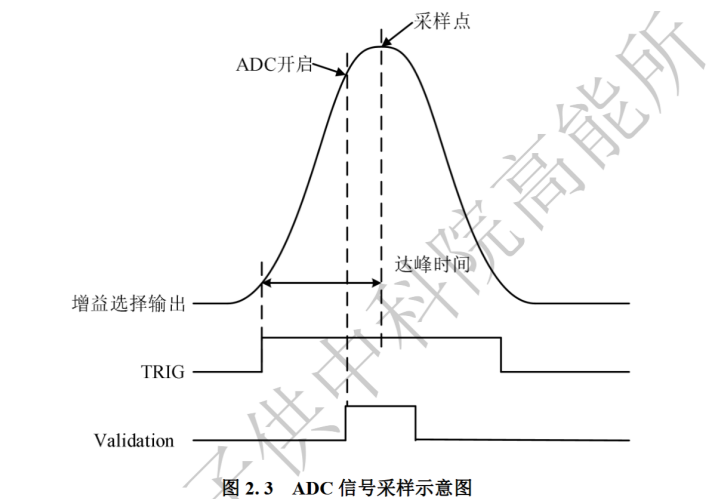
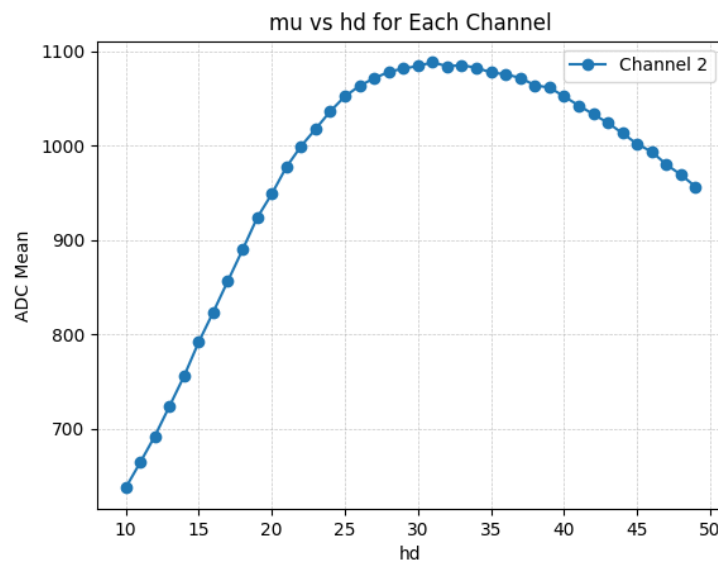
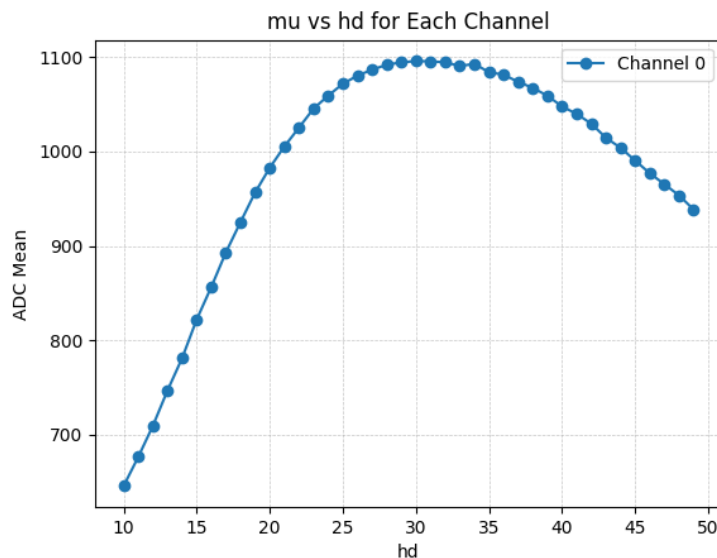
- Hold delay扫描

- 通过电荷注入板注入信号

- 逐个打开每个通道

- 低阈值设定为基线+5

- 计算每次采集数据的ADC均值



MPT2321 readout development

Optimization of configure parameter

- Hold delay 扫描

